

# 3-V TO 5.5-V MULTICHANNEL RS-232 1-MBit/s LINE DRIVER/RECEIVER

Check for Samples: MAX3237E

### FEATURES

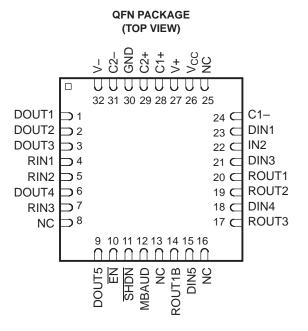
- Meets or Exceeds the Requirements of TIA/EIA-232-F and ITU v.28 Standards
- Operates With 3-V to 5.5-V V<sub>CC</sub> Supply
- Operates From 250 kbits/s to 1 Mbit/s
- Low Standby Current . . . 1 µA Typical
- External Capacitors . . . 4 × 0.1 µF
- Accepts 5-V Logic Input With 3.3-V Supply
- Designed to Be Interchangeable With Maxim MAX3237E
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II

DB. DV	v.	OR PW	PA	CKAGE				
_,	(TOP VIEW)							
	ſ	$\overline{\mathbf{t}}$		L				
C2+	<b>D</b>	1	28	] C1+				
GND	D	2	27	] V+				
C2-	D	3	26	] V <sub>CC</sub>				
V-		4	25	] C1–				
DOUT1	D	5	24	] DIN1				
DOUT2		6	23	DIN2				
DOUT3	D	7	22	] DIN3				
RIN1	٥	8	21	ROUT1				
RIN2	D	9	20	ROUT2				
DOUT4	D	10	19	] DIN4				
RIN3	D	11	18	ROUT3				
DOUT5	D	12	17	DIN5				
EN	ď	13	16	ROUT1B				
SHDN	ď	14	15	MBAUD				

- ESD Protection for RS-232 I/O Pins
  - ±15 kV Human-Body Model (HBM)
  - ±8 kV IEC61000-4-2, Contact Discharge
  - ±15 kV IEC61000-4-2, Air-Gap Discharge

#### **APPLICATIONS**

- Battery-Powered, Hand-Held, and Portable Equipment
- PDAs and Palmtop PCs
- Notebooks, Sub-Notebooks, and Laptops
- Digital Cameras
- Mobile Phones and Wireless Devices



### DESCRIPTION

The MAX3237E consists of five line drivers, three line receivers, and a dual charge-pump circuit with  $\pm$ 15-kV ESD protection pin to pin (serial-port connection pins, including GND). The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. This device operates at data signaling rates of 250 kbit/s in normal operating mode (MBAUD = GND) and 1Mbit/s when MBAUD = V<sub>CC</sub>. The driver output slew rate is a maximum of 30 V/µs.



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The MAX3237E transmitters are disabled and the outputs are forced into high-impedance state when the device is in shutdown mode (SHDN = GND) and the supply current falls to less than 1  $\mu$ A. Also, during shutdown, the onboard charge pump is disabled; V+ is lowered to V<sub>CC</sub>, and V- is raised toward GND. Receiver outputs also can be placed in the high-impedance state by setting enable (EN) high. ROUT1B remains active all the time, regardless of the EN and SHDN condition.

The MAX3237EC is characterized for operation from 0°C to 70°C. The MAX3237EI is characterized for operation from –40°C to 85°C.

T <sub>A</sub>	PACKAGED DEVICES <sup>(2)</sup>
	MAX3237ECDBR
0°C to 70°C	MAX3237ECPWR
	MAX3237ECRHBR (QFN package)
	MAX3237ECDWR
	MAX3237EIDBR
40°C to 95°C	MAX3237EIPWR
–40°C to 85°C	MAX3237EIRHBR (QFN package)
	MAX3237EIDWR

#### **AVAILABLE OPTIONS(1)**

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

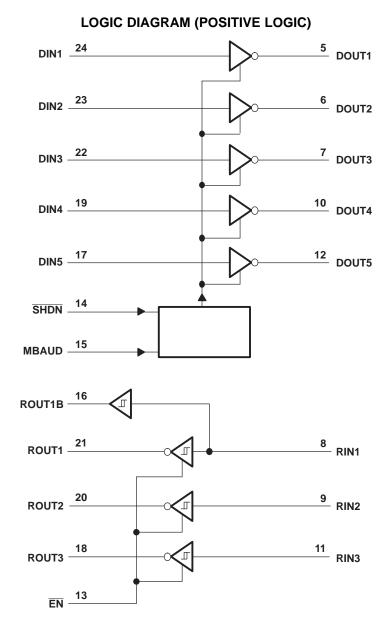
INPUT	S		OUTPUTS	
SHDN	EN	DOUT	ROUT	ROUT1B
0	0	Z <sup>(1)</sup>	Active	Active
0	1	Z <sup>(1)</sup>	Z <sup>(1)</sup>	Active
1	0	Active	Active	Active
1	1	Active	Z <sup>(1)</sup>	Active

#### Table 1. FUNCTION TABLE

(1) Z = high impedance (off)

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### ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range <sup>(2)</sup>		-0.3	6	V
V+	Positive-output supply voltage range <sup>(2)</sup>		-0.3	7	V
V–	Negative-output supply voltage range <sup>(2)</sup>		0.3	-7	V
V+ - V-	Supply voltage difference <sup>(2)</sup>			13	V
N/	Input voltago rongo	Driver (SHDN, MBAUD, EN)	-0.3	6	V
VI	Input voltage range	Receiver	-25	25	v
N/	Output up kang range	Driver	-13.2	13.2	V
Vo	Output voltage range	Receiver	-0.3	V <sub>CC</sub> + 0.3	v
	Short-circuit duration	DOUT to GND	Unlin	nited	
$\theta_{JA}$	Package thermal impedance <sup>(3)</sup>			62	°C/W
T <sub>stg</sub>	Storage temperature range		-65	150	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

All voltages are with respect to network GND. (2)

(3) The package thermal impedance is calculated in accordance with JESD 51-7.

### **RECOMMENDED OPERATING CONDITIONS**<sup>(1)</sup>

#### See Figure 5

				MIN	NOM	MAX	UNIT
	Supply voltage		$V_{CC} = 3.3 V$	3	3.3	3.6	V
			$V_{CC} = 5 V$	4.5	5	5.5	v
V	Driver and control high level input veltage	DIN, SHDN, MBAUD, EN	$V_{CC} = 3.3 V$	2		5.5	V
VIH	Driver and control high-level input voltage DIN, SH	DIN, SEDN, MBAUD, EN	$V_{CC} = 5 V$	2.4		5.5	v
VIL	Driver and control low-level input voltage	DIN, SHDN, MBAUD, EN		0		0.8	V
VI	Receiver input voltage			-25		25	V
-			MAX3237EC	0		70	0°
IA	Operating free-air temperature		MAX3237EI	-40		85	

(1) Test conditions are C1–C4 = 0.1  $\mu F$  at V<sub>CC</sub> = 3 V to 5 V.

### ELECTRICAL CHARACTERISTICS<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER		TEST CONDITIONS	MIN TYP <sup>(2)</sup>	MAX	UNIT
I <sub>I</sub>	Input leakage current	DIN, SHDN, MBAUD, EN		9	18	μA
			No load, $\overline{\text{SHDN}} = V_{CC}$	0.5	2	mA
Icc	Supply current		SHDN = GND	1	10	μA
	(T <sub>A</sub> = 25°C)	Shutdown supply current	$\overline{\text{SHDN}} = \text{RIN} = \text{GND},$ DIN = GND or V <sub>CC</sub>	10	300	nA

(1)

Test conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3 V to 5 V. All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C. (2)



#### DRIVER SECTION ELECTRICAL CHARACTERISTICS<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	TEST CONDI	TIONS	MIN	TYP <sup>(2)</sup>	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = GND	5	5.4		V
V <sub>OL</sub>	Low-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	$DIN = V_{CC}$	-5	-5.4		V
I <sub>IH</sub>	High-level input current	$V_{I} = V_{CC}$			±0.01	±1	μA
I <sub>IL</sub>	Low-level input current	V <sub>I</sub> at GND			±0.01	±1	μA
I <sub>OS</sub>	Short-circuit output current <sup>(3)</sup>	$V_{CC} = 3.6 V \text{ or } 3.3 V,$	$V_0 = 0 V$			±60	mA
r <sub>o</sub>	Output resistance	$V_{CC}$ , V+, and V- = 0 V,	$V_0 = \pm 2 V$	300	50k		Ω

 Test conditions are C1–C4 = 0.1 μF at V<sub>CC</sub> = 3 V to 5 V.
 All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C.
 Short-circuit durations should be controlled to prevent exceeding the device absolute power-dissipation ratings, and not more than one output should be shorted at a time.

#### DRIVER SECTION SWITCHING CHARACTERISTICS<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

I	PARAMETER		TEST CONDITIONS		MIN	TYP <sup>(2)</sup>	MAX	UNIT
		C <sub>L</sub> = 1000 pF, MBAUD = GND			250			
	Maximum data rate	$\begin{array}{l} C_{L} = 1000 \ \text{pF}, \\ V_{CC} = 4.5 \ \text{V to } 5.5 \ \text{V}, \\ \text{MBAUD} = V_{CC} \end{array}$	$R_L = 3 k\Omega$ , 1 DIN switching, See Figure 1		1000			kbit/s
		$\begin{array}{l} C_{L} = 250 \text{ pF}, \\ V_{CC} = 3 \text{ V to } 4.5 \text{ V}, \\ \text{MBAUD} = V_{CC} \end{array}$			1000			
t <sub>sk(p)</sub>	Pulse skew <sup>(3)</sup>		C <sub>L</sub> = 150 pF to 2500 pF, R <sub>L</sub> = 3 kΩ to 7 kΩ, MBAUD = V <sub>CC</sub> or GND, See Figure 2			100		ns
	Slew rate,	$V_{CC} = 3.3 V_{,}$	C <sub>1</sub> = 150 pF to 1000 pF	MBAUD = GND	6		30	
SR(tr)	transition region	$R_L = 3 k\Omega \text{ to } 7 k\Omega$ ,	$C_{L} = 150 \text{ pr}$ to 1000 pr	$MBAUD=V_{CC}$	24		150	V/µs
	(see Figure 1)	$T_A = 25^{\circ}C$	$C_L$ = 150 pF to 2500 pF,	MBAUD = GND	4		30	

## **RECEIVER SECTION ELECTRICAL CHARACTERISTICS**<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>(2)</sup>	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -1 \text{ mA}$	$V_{CC} - 0.6$	V <sub>CC</sub> – 0.1		V
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 1 mA			0.4	V
V	Depitive going input threshold veltage	$V_{\rm CC} = 3.3 \text{ V}$		1.5	2.4	V
V <sub>IT+</sub>	Positive-going input threshold voltage	$V_{CC} = 5 V$		2	2.4	V
V	Negative going input threshold veltage	$V_{CC} = 3.3 V$	0.6	1.1		V
V <sub>IT-</sub>	Negative-going input threshold voltage	$V_{CC} = 5 V$	0.8	1.5		v
V <sub>hys</sub>	Input hysteresis (V <sub>IT+</sub> – V <sub>IT–</sub> )			0.5		V
I <sub>oz</sub>	Output leakage current	$\overline{EN} = V_{CC}$		±0.05	±10	μA
r <sub>i</sub>	Input resistance	$V_1 = \pm 3 \text{ V to } \pm 25 \text{ V}$	3	5	7	kΩ

(1)

Test conditions are C1–C4 = 0.1 mF at V<sub>CC</sub> = 3 V to.5 V. All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C. (2)

## **RECEIVER SECTION SWITCHING CHARACTERISTICS**<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TYP <sup>(2)</sup>	UNIT
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	C <sub>L</sub> = 150 pF, See Figure 3	150	ns
t <sub>PHL</sub>	Propagation delay time, high- to low-level output	C <sub>L</sub> = 150 pF, See Figure 3	150	ns
t <sub>en</sub>	Output enable time	$C_L = 150 \text{ pF}, R_L = 3 \text{ k}\Omega$ , See Figure 4	2.6	μs
t <sub>dis</sub>	Output disable time	$C_L = 150 \text{ pF}, R_L = 3 \text{ k}\Omega$ , See Figure 4	2.4	μs
t <sub>sk(p)</sub>	Pulse skew <sup>(3)</sup>	See Figure 3	50	ns

(1)

(2)

Test conditions are C1–C4 = 0.1  $\mu F$  at V<sub>CC</sub> = 3 V to 5 V. All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C. Pulse skew is defined as |t<sub>PLH</sub> - t<sub>PHL</sub>| of each channel of the same device. (3)

### **ESD PROTECTION**

PIN	TEST CONDITIONS		UNIT
	НВМ	±15	
DOUT, RIN	IEC61000-4-2, Contact Discharge	±8	kV
	IEC61000-4-2, Air-Gap Discharge	±15	

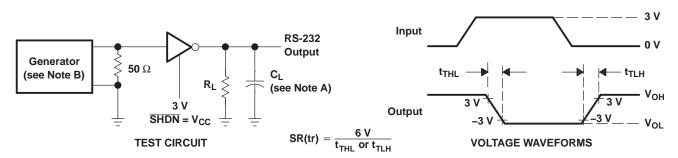


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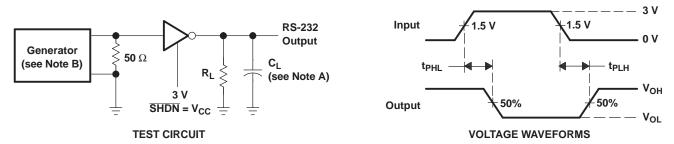
#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_0$  = 50  $\Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

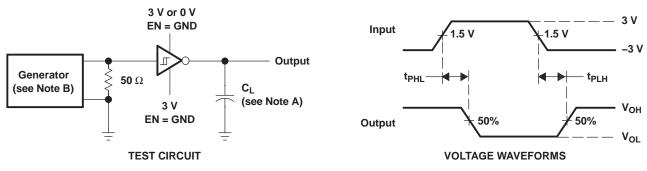
#### Figure 1. Driver Slew Rate



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

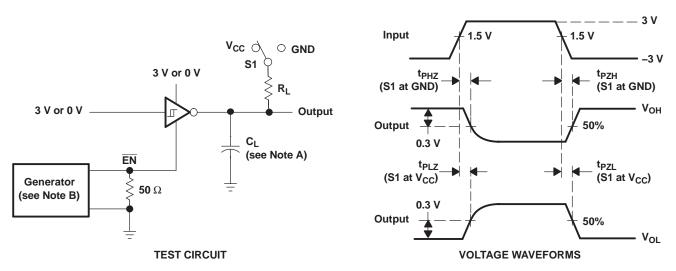
B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_0$  = 50  $\Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

Figure 2. Driver Pulse Skew



NOTES: A. C<sub>L</sub> includes probe and jig capacitance. B. The pulse generator has the following characteristics:  $Z_0 = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns.  $t_f \le 10$  ns.

Figure 3. Receiver Propagation Delay Times



**PARAMETER MEASUREMENT INFORMATION (continued)** 

- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. The pulse generator has the following characteristics:  $Z_0 = 50 \Omega$ , 50% duty cycle,  $t_r \le 10 \text{ ns}$ ,  $t_f \le 10 \text{ ns}$ .
    - C.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
    - D.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .

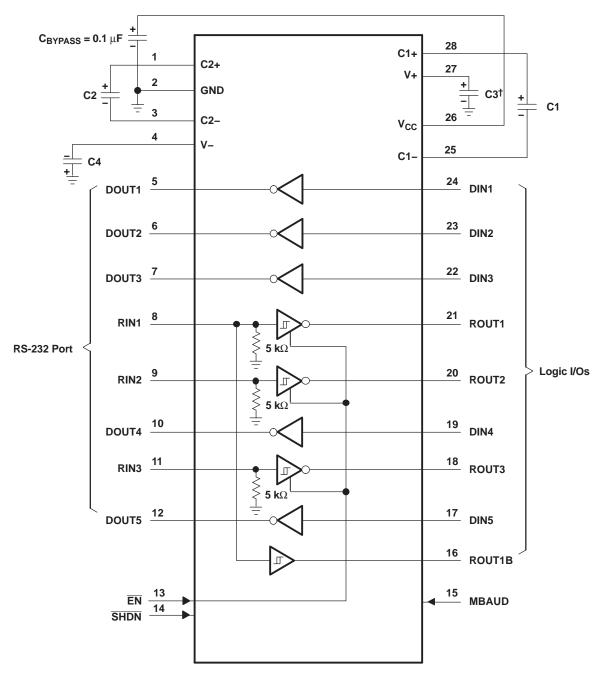
#### Figure 4. Receiver Enable and Disable Times

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APPLICATION INFORMATION

 $^{\dagger}$  C3 can be connected to V\_CC or GND.

NOTES: A. Resistor values shown are nominal.

B. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.

#### V<sub>CC</sub> vs CAPACITOR VALUES

V <sub>CC</sub>	C1	C2, C3, and C4
$\begin{array}{c} 3.3 \text{ V} \pm 0.15 \text{ V} \\ 3.3 \text{ V} \pm 0.3 \text{ V} \\ 5 \text{ V} \pm 0.5 \text{ V} \\ 3 \text{ V} \text{ to } 5.5 \text{ V} \end{array}$	0.1 μF 0.22 μF 0.047 μF 0.22 μF	0.1 μF 0.22 μF 0.33 μF 1 μF

#### Figure 5. Typical Operating Circuit and Capacitor Values



24-Aug-2018

### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	•	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
MAX3237ECDB	ACTIVE	SSOP	DB	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDBG4	ACTIVE	SSOP	DB	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDBR	ACTIVE	SSOP	DB	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDBRG4	ACTIVE	SSOP	DB	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDW	ACTIVE	SOIC	DW	28	20	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDWG4	ACTIVE	SOIC	DW	28	20	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDWR	ACTIVE	SOIC	DW	28	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MP237EC	Samples
MAX3237ECPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MP237EC	Samples
MAX3237ECPWRG4	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	MP237EC	Samples
MAX3237EIDB	ACTIVE	SSOP	DB	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3237EI	Samples
MAX3237EIDBR	ACTIVE	SSOP	DB	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3237EI	Samples
MAX3237EIDW	ACTIVE	SOIC	DW	28	20	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3237EI	Samples
MAX3237EIPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP237EI	Samples
MAX3237EIPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP237EI	Samples

(1) The marketing status values are defined as follows:
 ACTIVE: Product device recommended for new designs.
 LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
 NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.



24-Aug-2018

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available. **OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(<sup>5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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## PACKAGE MATERIALS INFORMATION

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#### TAPE AND REEL INFORMATION





### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
MAX3237ECDBR	SSOP	DB	28	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
MAX3237ECDWR	SOIC	DW	28	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
MAX3237ECPWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1
MAX3237EIDBR	SSOP	DB	28	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
MAX3237EIPWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1

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## PACKAGE MATERIALS INFORMATION

12-Feb-2019



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
MAX3237ECDBR	SSOP	DB	28	2000	367.0	367.0	38.0
MAX3237ECDWR	SOIC	DW	28	1000	350.0	350.0	66.0
MAX3237ECPWR	TSSOP	PW	28	2000	367.0	367.0	38.0
MAX3237EIDBR	SSOP	DB	28	2000	367.0	367.0	38.0
MAX3237EIPWR	TSSOP	PW	28	2000	367.0	367.0	38.0

DW (R-PDSO-G28)

PLASTIC SMALL OUTLINE



NOTES:

A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AE.



PW (R-PDSO-G28)

PLASTIC SMALL OUTLINE



NOTES:

A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 B. This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153



## LAND PATTERN DATA



NOTES: All linear dimensions are in millimeters. Α.

- B. This drawing is subject to change without notice.
  C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.

E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# **DB0028A**



## **PACKAGE OUTLINE**

## SSOP - 2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.



# DB0028A

# **EXAMPLE BOARD LAYOUT**

### SSOP - 2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# DB0028A

# **EXAMPLE STENCIL DESIGN**

## SSOP - 2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



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